- 22 -

ABSTRACT

The present invention provides a probe for non-destructive testing of items. The probe is movable over a surface of a test item and includes a displacement sensor means for providing a displacement signal indicative of the spatial displacement of the probe over the test item as the probe is moved over the test item. The invention also provides the above-defined probe with a receiver for receiving a return signal from the non-destructive testing of the item and a non-destructive testing system comprising the probe.

10

5